

GET AHEAD WITH NXP'S PN5180 FRONTEND - DESIGN YOUR POS TERMINAL WITH EMVCO (L1) CERTIFICATION

SESSION 2: PN5180 FOR EMVCO L1 CONTACTLESS CERTIFICATION

PABLO FUENTES

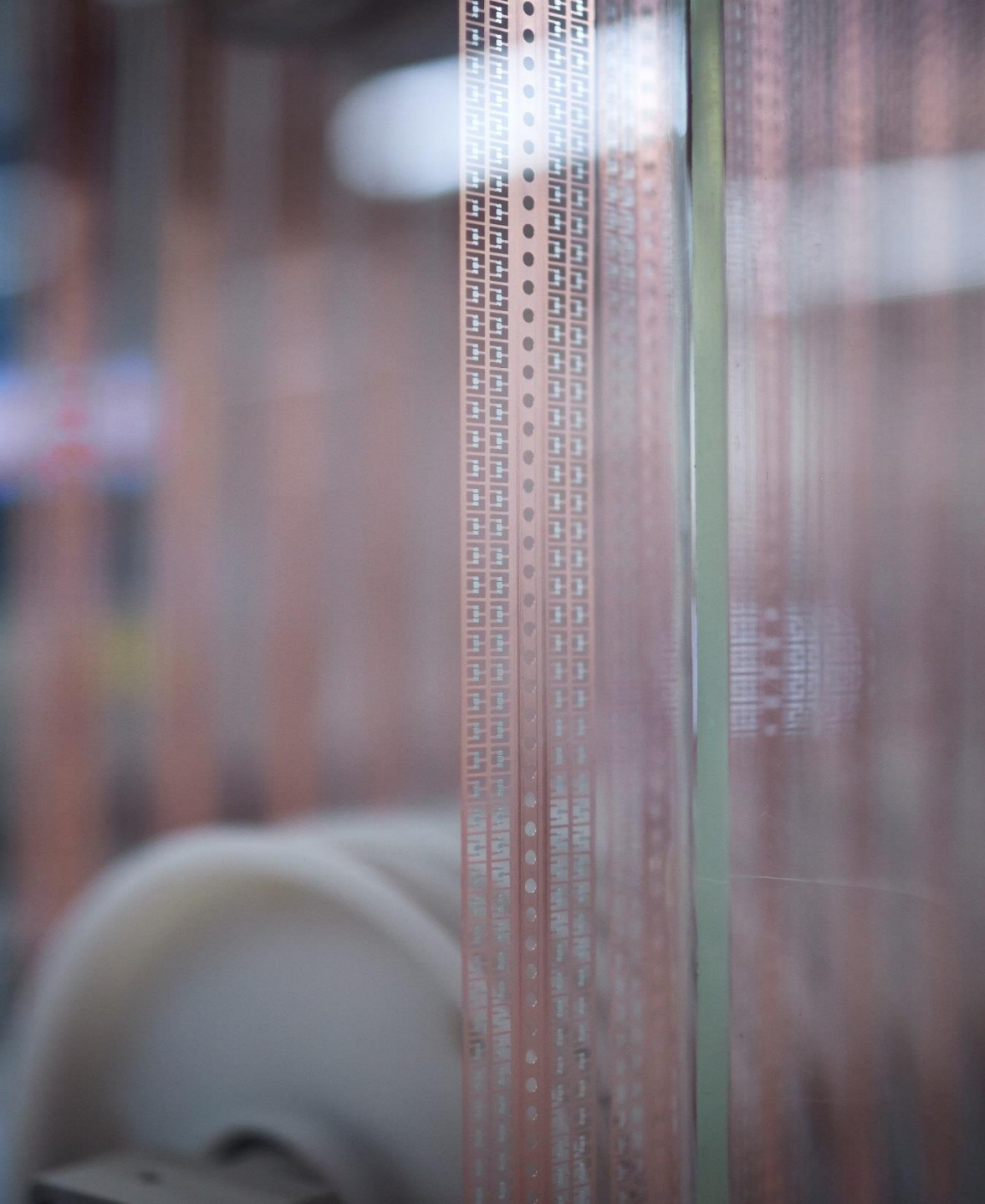
JULY 2018



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SECURE CONNECTIONS
FOR A SMARTER WORLD



Get ahead with NXP's PN5180 Frontend - Design your POS terminal with EMVCo (L1) certification

Session I, **28th June**

EMVCo L1 Contactless certification process

<https://attendee.gotowebinar.com/rt/3034896575464625666>

Session II, **17th July**

PN5180 for EMVCo L1 Contactless certification

<https://register.gotowebinar.com/rt/5226533311901393666>



Agenda

- Recap from session I
- PN5180 Antenna design considerations
- Power tests
- Waveform tests
- Reception tests
- PN5180 Ecosystem
- More support



Recap from session I



Recap from session I

EMV Analog L1 Test cases

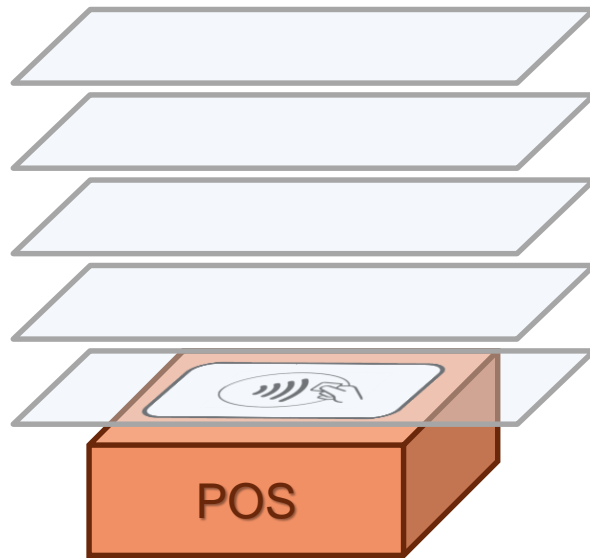
- Power tests
- Waveform tests
- Reception tests

Test Code	Test Name	0	0	0	0	0	1	1	1	1	1	2	2	2	2	2	3	3	3	3	3	4	4	4	4	4
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		0	0	3	6	9	0	0	3	6	9	0	0	3	6	9	0	0	3	6	9	0	0	3	6	9
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Recap from session I

EMV Analog L1 Test cases

- Power tests
- Waveform tests
- Reception tests

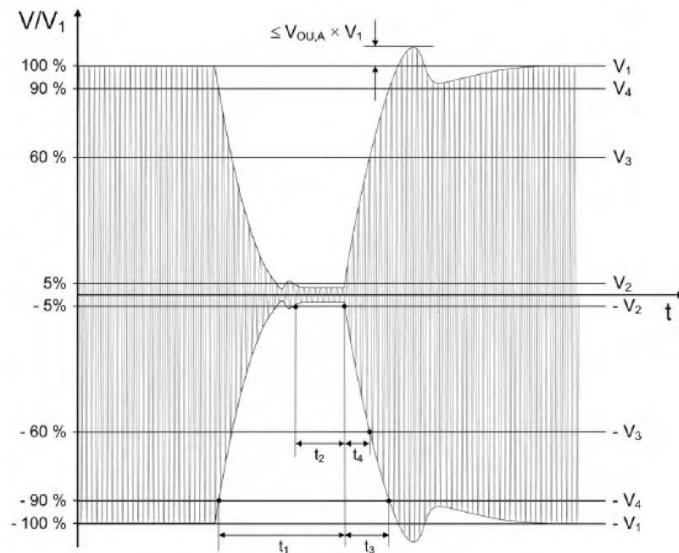


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Recap from session I

EMV Analog L1 Test cases

- Power tests
- **Waveform tests**
- Reception tests



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Recap from session I

EMV Analog L1 Test cases

- Power tests
- Waveform tests
- **Reception tests**



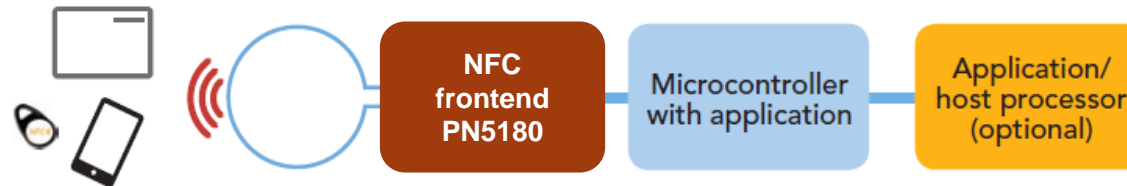
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Recap from session I

PN5180 key features



- Multi-protocol and high RF performance
- Full NFC Forum and EMVCo compliant frontend
- Flexible low power card detection
- Efficient, robust and reliable operation even in harsh conditions
- Maximum interoperability for next generation of NFC phones
- Onboard Dynamic Power Control (DPC) for optimized RF performance
- Fast SPI host interface with optimized commands for use with 32-bit host controllers
- Small, industry-standard packages with BGA form factor for PCI compliancy



PN5180 Antenna design considerations for EMVCo

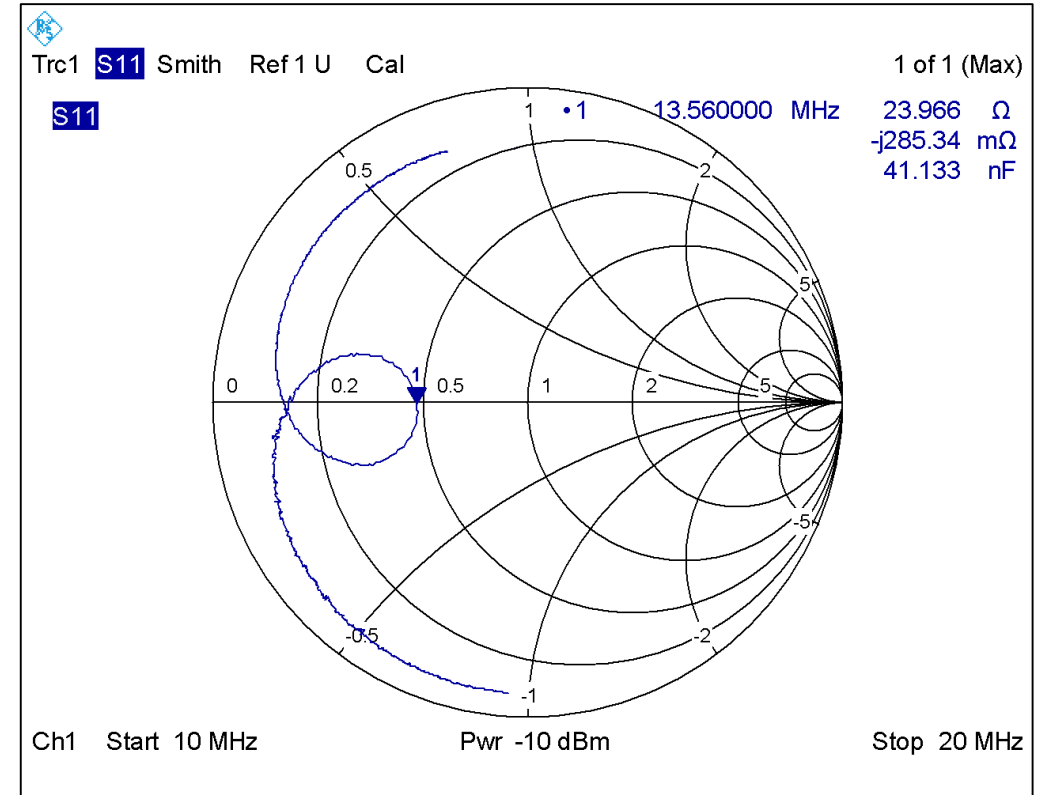


Antenna design considerations for EMVCo

Antenna tuning

Recommendations for an optimum antenna tuning of the PN5180:

- Use a symmetrical tuning
 - Provides more power transfer
 - Better transfer function
 - Requires current limiter/controller
- Adjust EMC filter and matching network
 - $L_0 \geq \frac{L_{AntennaCoil}}{2}$ to ensure proper AGC-ITVDD correlation
 - Recommended EMC cut off freq: $f_{EMC} \approx 14.3...14.7MHz$
- Set Rx resistor:
 - Reader Mode only design: AGC value in free air around 600_{dec}
 - Full NFC design: AGC value in free air around 300_{dec}
- EMVCo bitrate (106kbps) allows for a higher Q factor
 - Positive for the power gain
 - Might cause issues in waveform tests



Symmetrical tuning example

Antenna design considerations for EMVCo

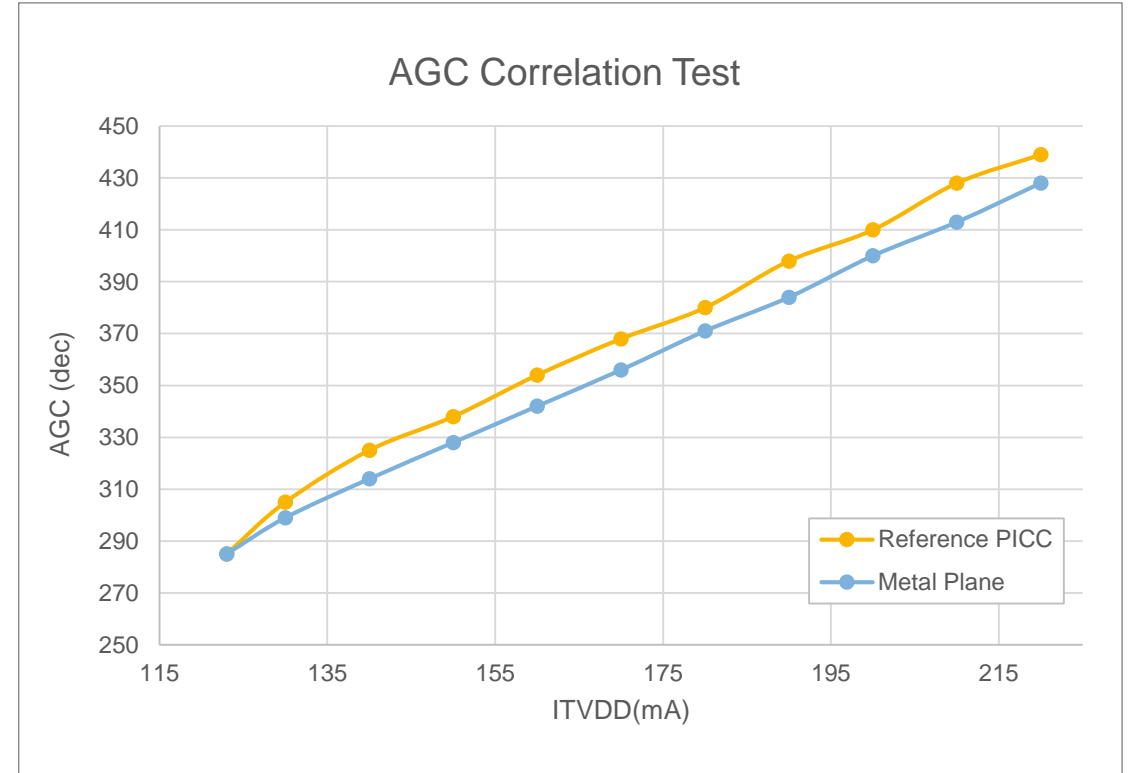
AGC Correlation and DPC calibration

1. Check AGC and ITVDD correlation

- Use different loads (e.g., reference PICC, metal plane...)
- It prevents unexpected behavior with other loads

2. Calibrate DPC:

- Keep transmitter current below 250 mA (recom. ~230mA)
- Use maximum power settings for plane $z = 4$
- Set different gears depending on the z plane



Antenna design considerations for EMVCo

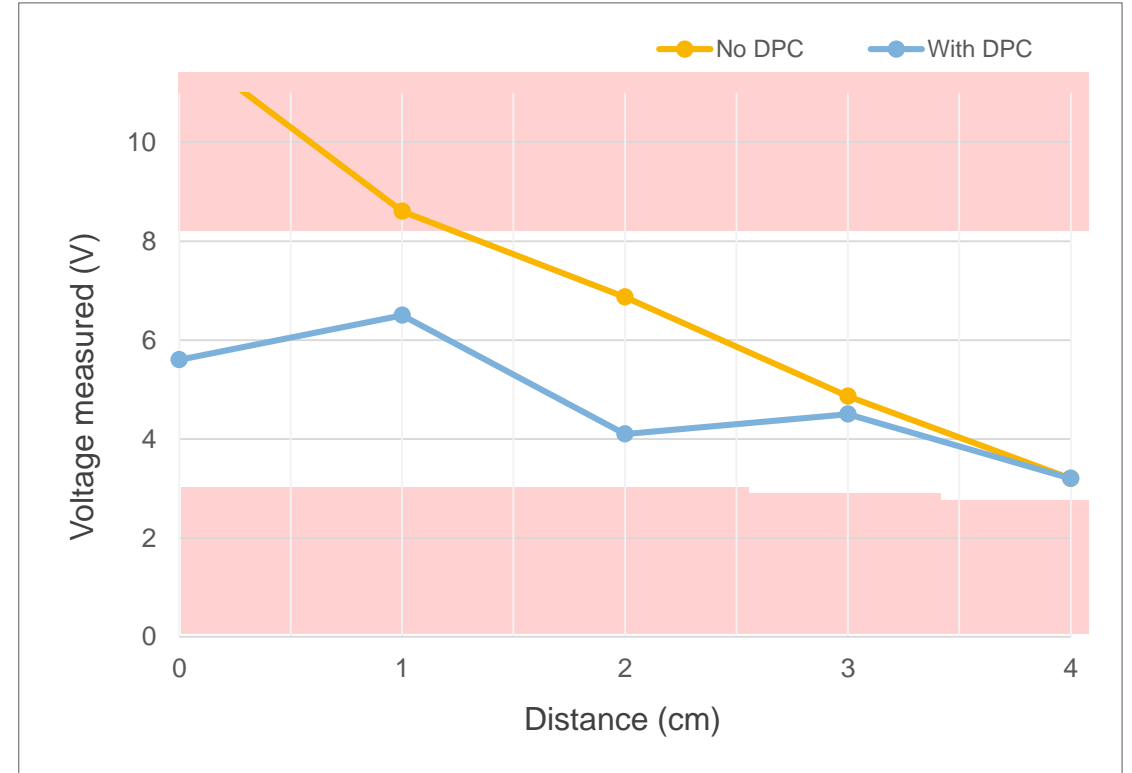
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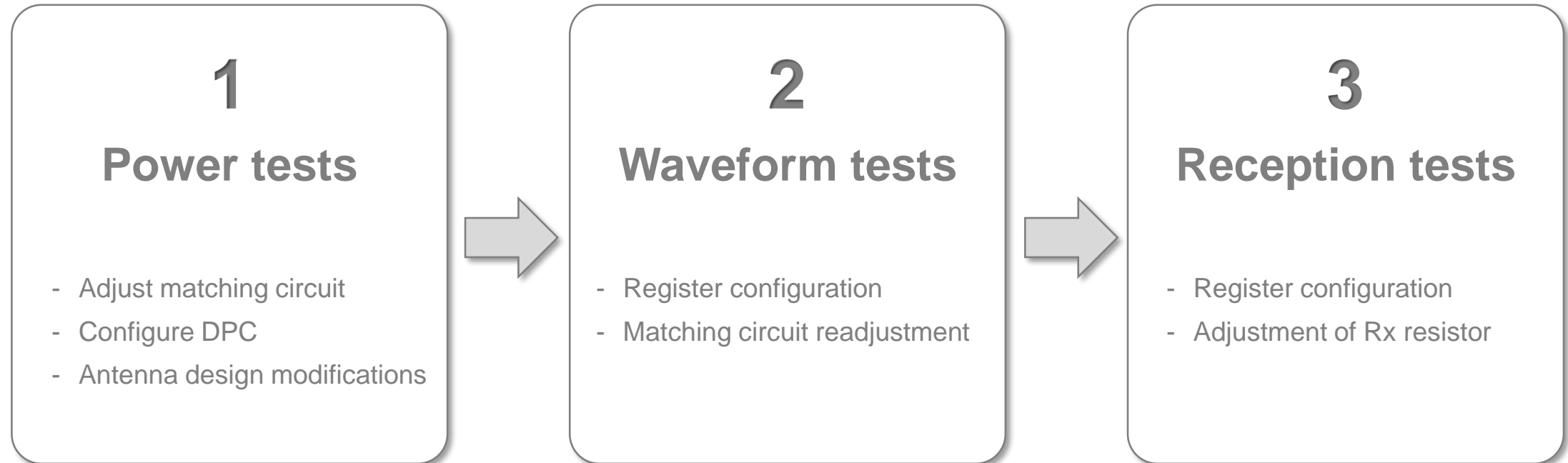
EMV L1 Analog tests

Debugging process



EMV L1 Analog tests

Debugging process



EMV L1 Analog Power tests



EMV L1 Analog - Power tests

Content

- Test setup
- Performing tests
- Critical positions
- Debugging hints

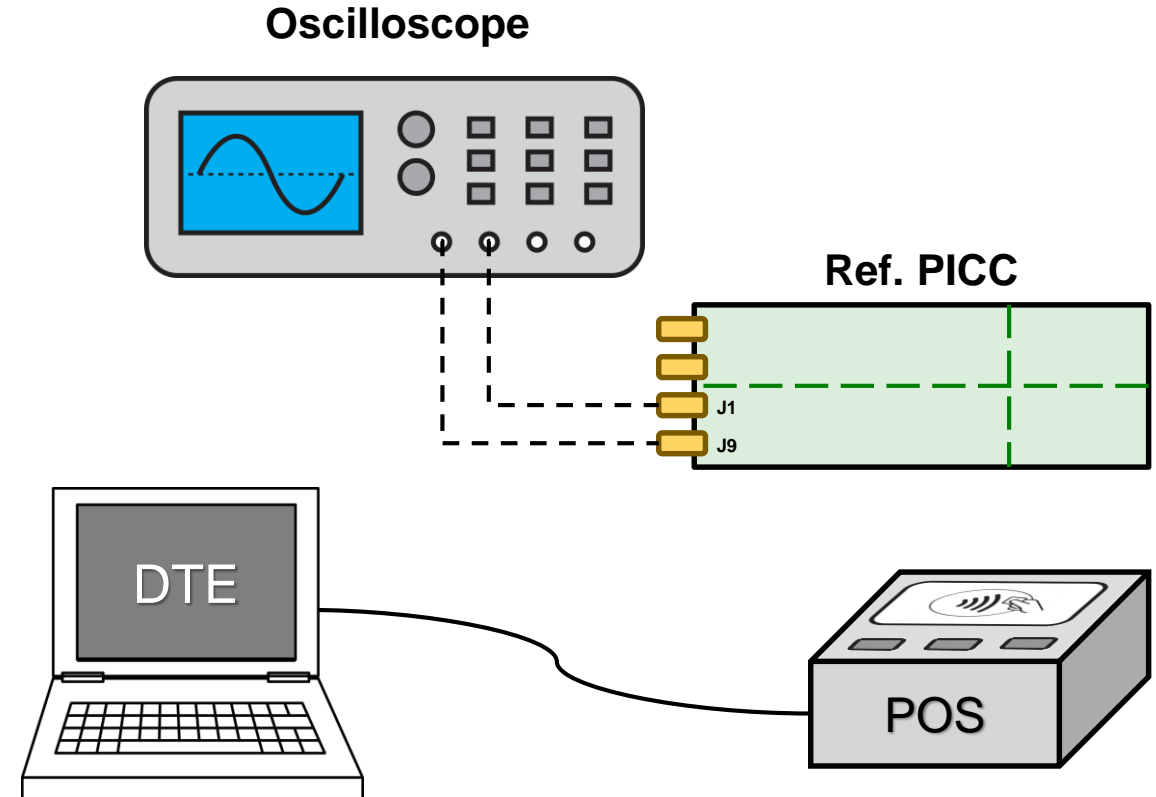


EMV L1 Analog - Power tests

Test setup



1. Connect J9 of ref PICC to oscilloscope Ch1
2. Connect J1 of ref PICC to oscilloscope Ch2
3. Set ref PICC J8 in non-linear load mode (1-4)
4. Configure oscilloscope trigger:
 - Ch1, Rising edge
5. Set the DTE in loopback mode

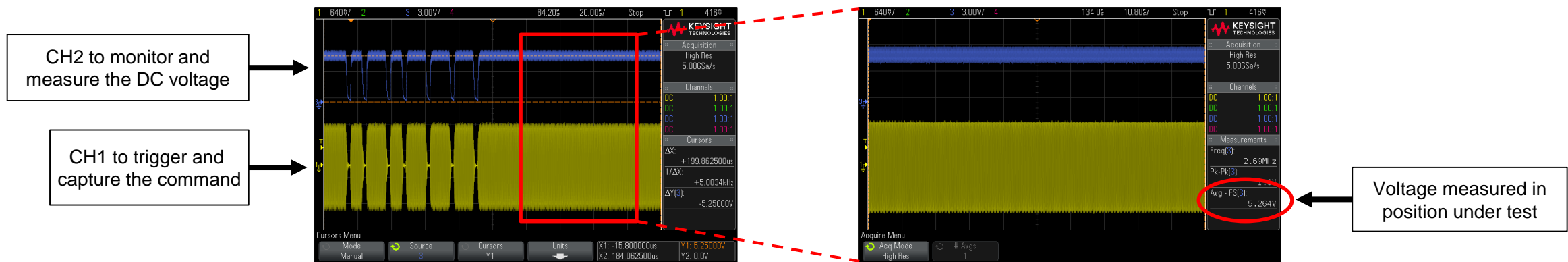


EMV L1 Analog - Power tests

Performing tests

- 1 Power tests
- 2 Waveform tests
- 3 Reception tests

1. Place the reference PICC in the target position
2. Send a REQA command
3. Measure voltage level at DC_OUT jumper in a non-modulated period

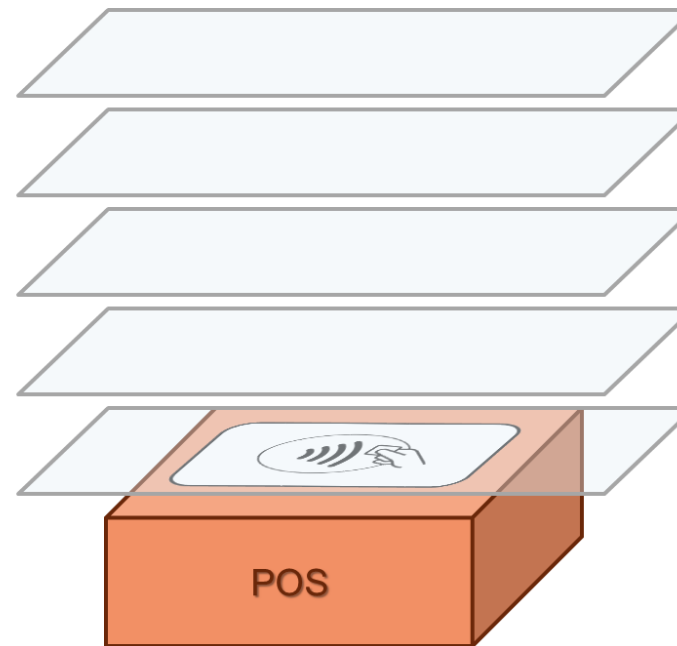


EMV L1 Analog - Power tests

Performing tests

1. Place the reference PICC in the target position
2. Send a REQA command
3. Measure voltage level at DC_OUT jumper in a non modulated period

$2,55\text{ V} < V_{4XX} < 8,1\text{V}$	Z = 4
$2,775\text{ V} < V_{3XX} < 8,1\text{V}$	Z = 3
$3\text{ V} < V_{2XX} < 8,1\text{V}$	Z = 2
$3,05\text{ V} < V_{1XX} < 8,1\text{V}$	Z = 1
$3,1\text{ V} < V_{0XX} < 8,1\text{V}$	Z = 0



EMV L1 Analog - Power tests

Critical positions

1 Power tests	2 Waveform tests	3 Reception tests
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1. External positions in plane Z = 4 cm

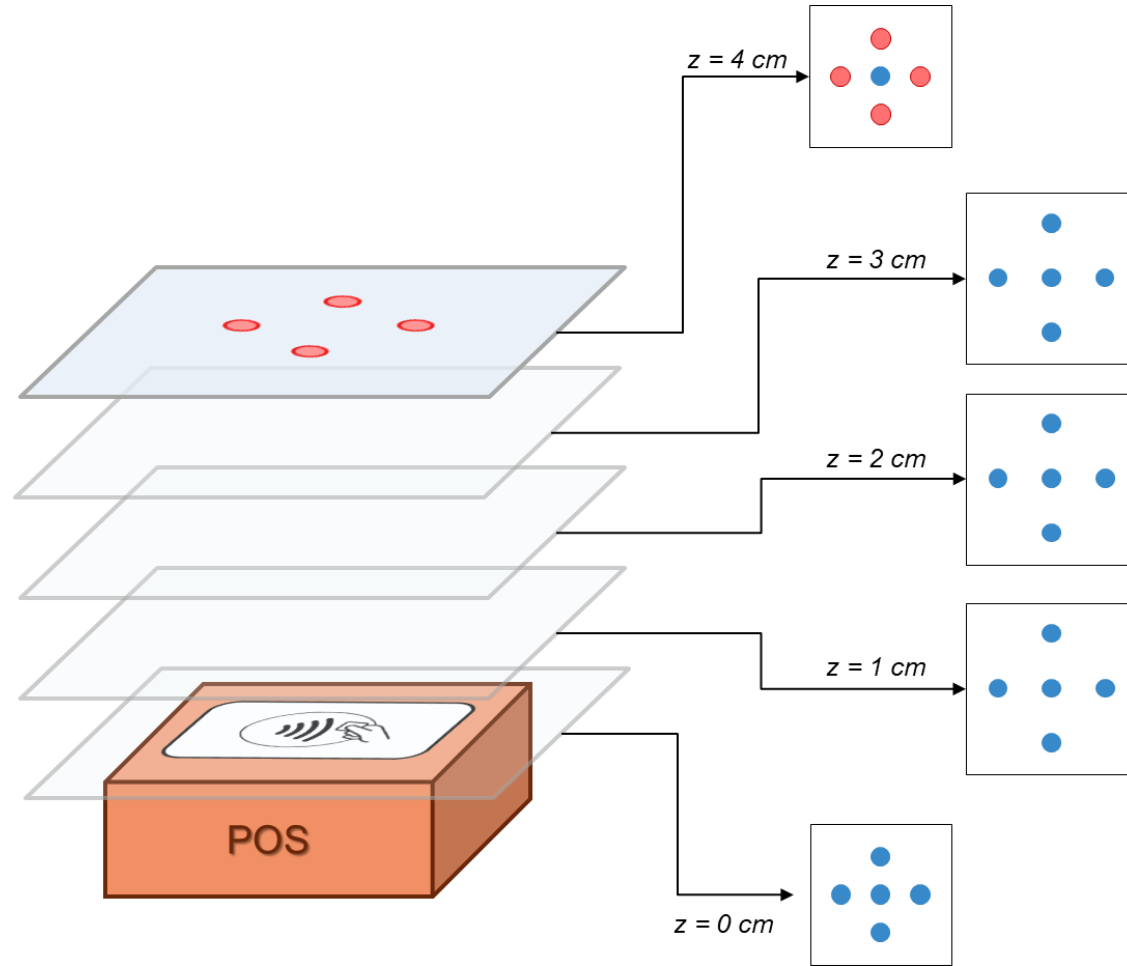
- Position (4, 1, 0)
- Position (4, 1, 3)
- Position (4, 1, 6)
- Position (4, 1, 9)

2. External positions in plane Z = 3 cm

- Position (3, 2, 0)
- Position (3, 2, 3)
- Position (3, 2, 6)
- Position (3, 2, 9)

3. Central position in plane Z = 1 cm

- Position (1, 0, 0)



EMV L1 Analog - Power tests

Critical positions

1
Power tests

2
Waveform tests

3
Reception tests

1. External positions in plane Z = 4 cm

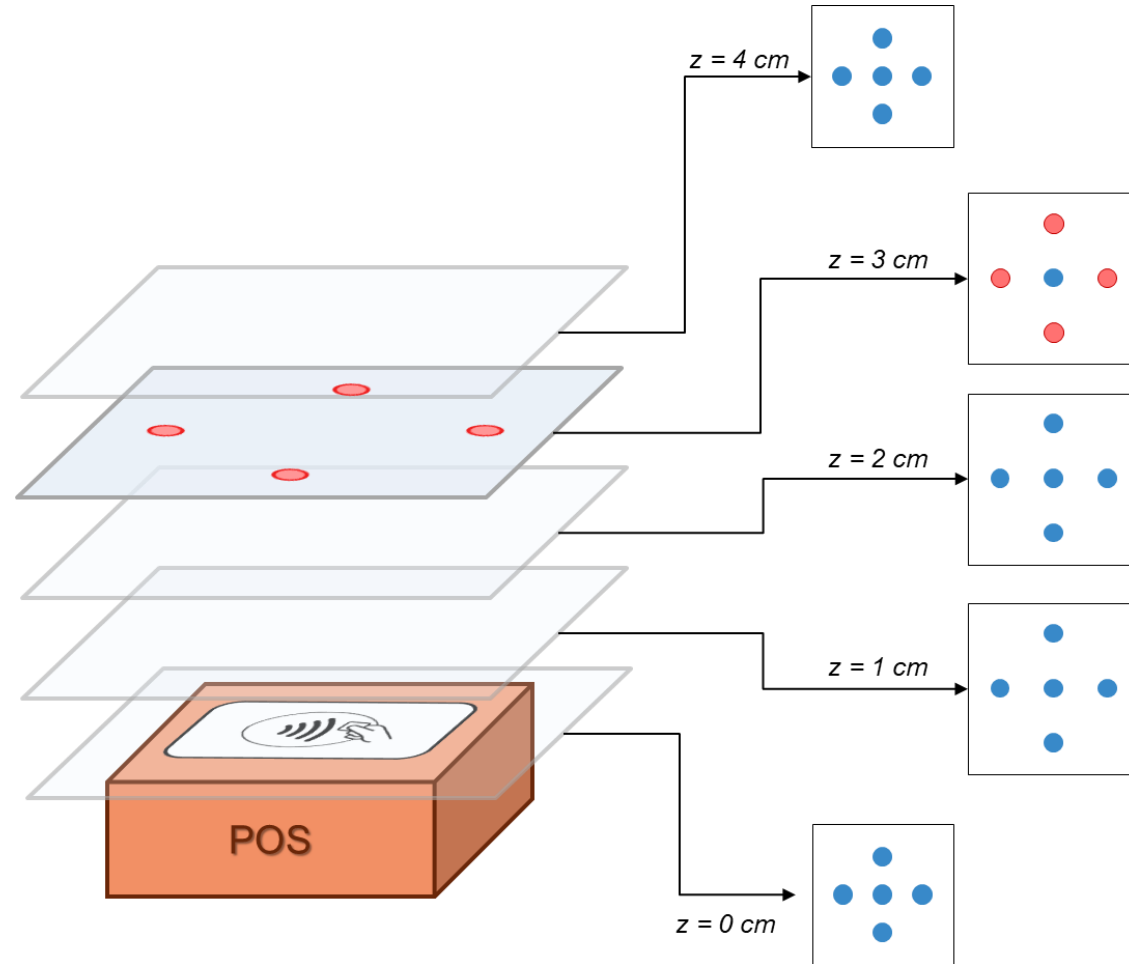
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EMV L1 Analog - Power tests

Critical positions

1 Power tests	2 Waveform tests	3 Reception tests
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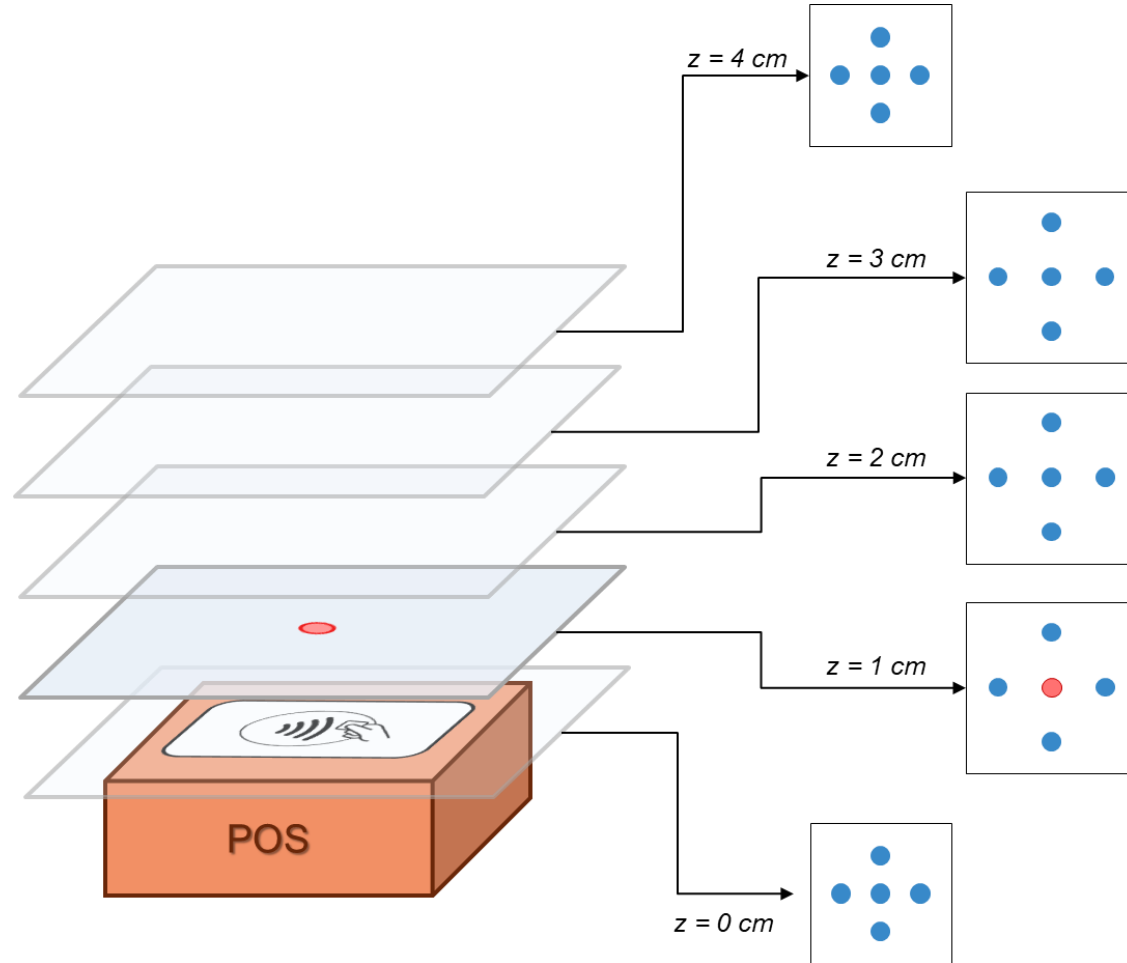
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EMV L1 Analog - Power tests

Debugging hints

1
Power tests

2
Waveform tests

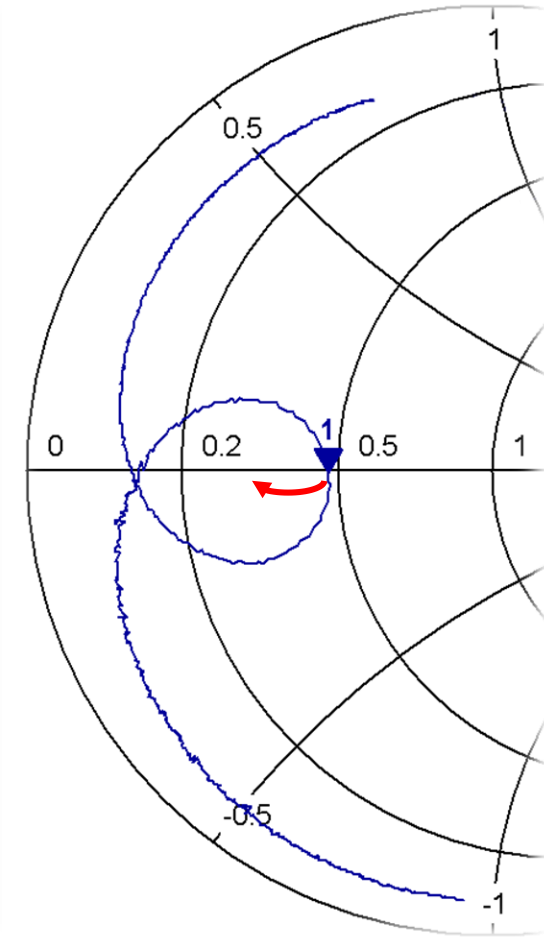
3
Reception tests

Problem 1: Lack of voltage at certain position

1. Make sure that the PN5180 is working in gear 0 at full power:
 - Check DPC_CURRENT_GEAR in register RF_STATUS (1Dh)
2. Reduce the impedance to drive more current to the antenna
 - Check that transmitter current does not exceed the limit !!
3. Evaluate changes in antenna design (add ferrite, change antenna position...)

Problem 2: Voltage measured over the limit at certain position

1. Use a lower power configuration for that particular gear



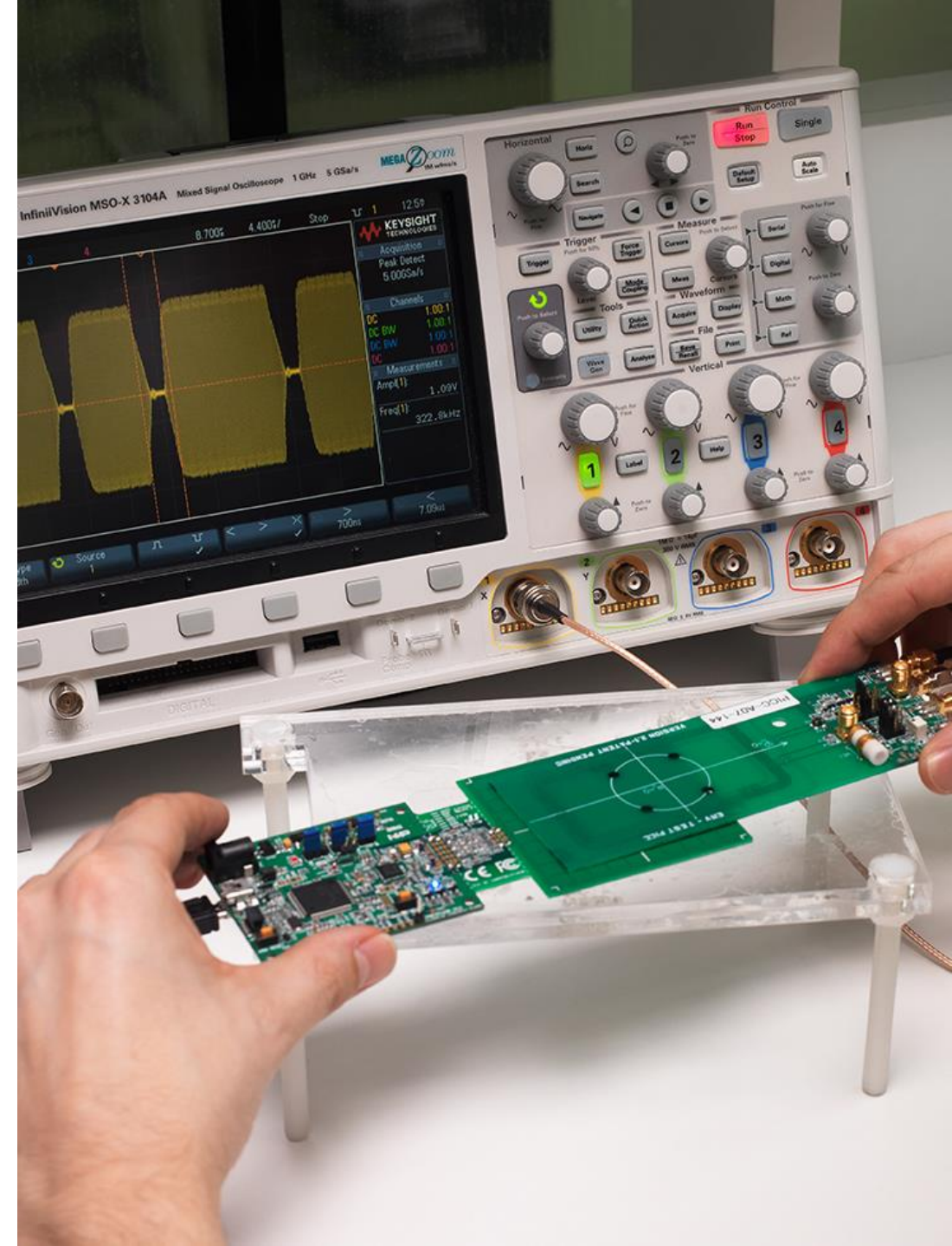
EMV L1 Analog Waveform tests



EMV L1 Analog - Waveform tests

Content

- Evaluation tools
- Test setup
- Performing tests
- Debugging hints



EMV L1 Analog - Waveform tests

Evaluation tools

1
Power
tests

2
Waveform
tests

3
Reception
tests

Option 1

EMVCo Analog L1 Testbench



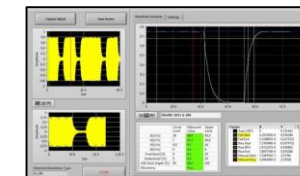
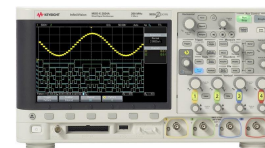
Option 2

Reference PICC + Oscilloscope + Evaluation SW

Suggestion:

CETECOM Wavechecker SW

PC tool that takes screenshots from the oscilloscope, reads the data, checks the pulse shapes and compares it with the EMV limits.

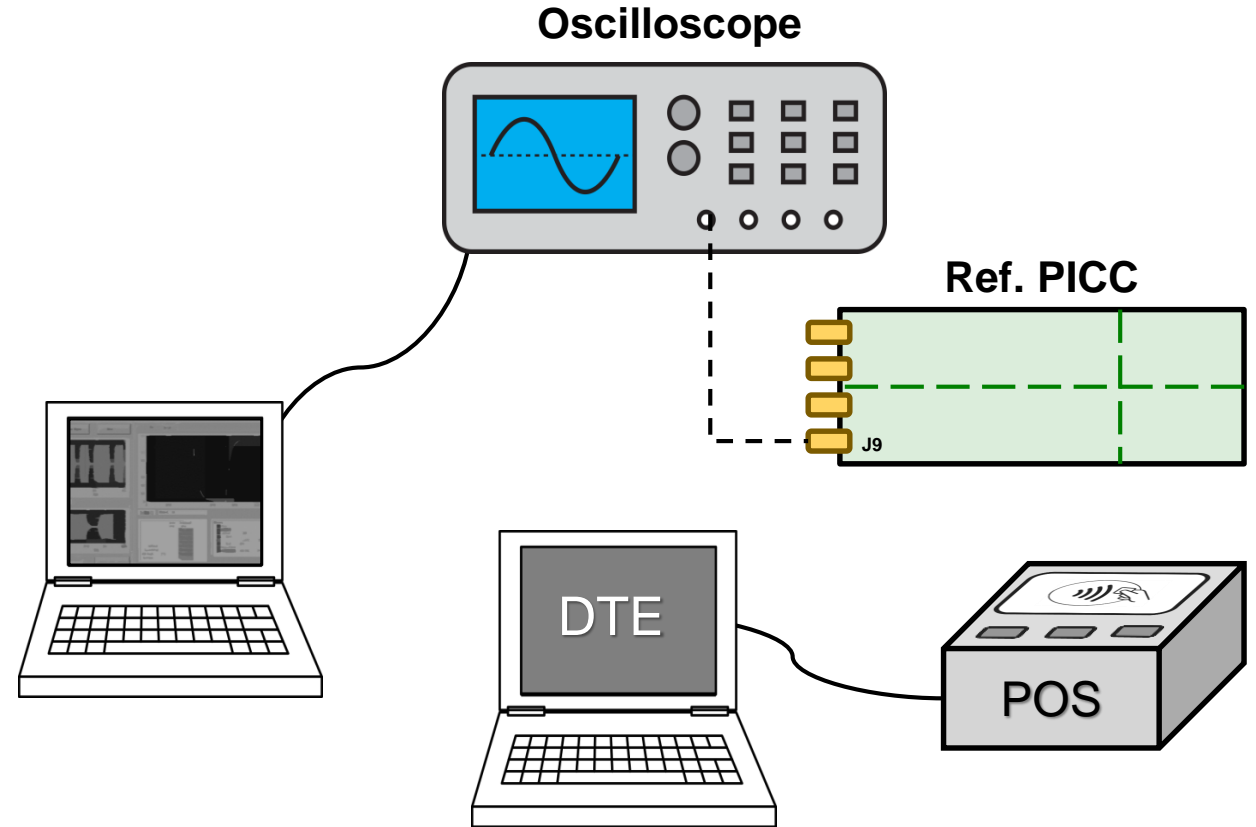


EMV L1 Analog - Waveform tests

Test setup

1 Power tests	2 Waveform tests	3 Reception tests
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1. Connect J9 of ref PICC to oscilloscope Ch1
2. Set ref PICC J8 in fixed load mode (1-4)
3. Configure oscilloscope trigger to capture modulation
4. Set the DTE in loopback mode



EMV L1 Analog - Waveform tests

Debugging tests

1
Power
tests

2
Waveform
tests

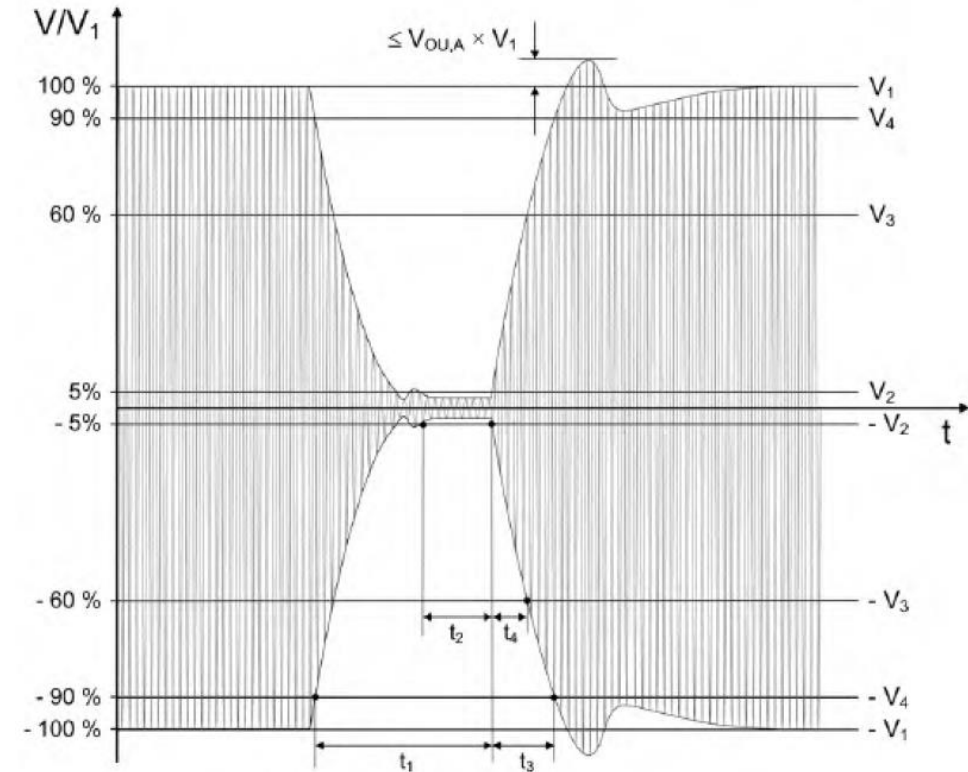
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Reception
tests

Type A:

- TA121: t_1
- TA122: Monotonic Decrease
- TA123: Ringing
- TA124: t_2
- TA125: t_3 and t_4
- TA127: Monotonic Increase
- TA128: Overshoot

PN5180 Relevant parameters:

- TX_CLK_MODE_RM (RF_CONTROL_TX_CLK)
- Rise and Fall times (RF_CONTROL_TX)
- Overshoot prevention



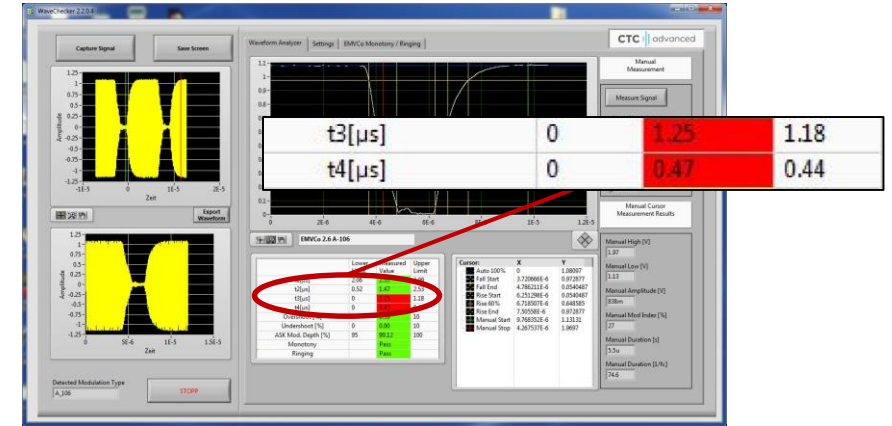
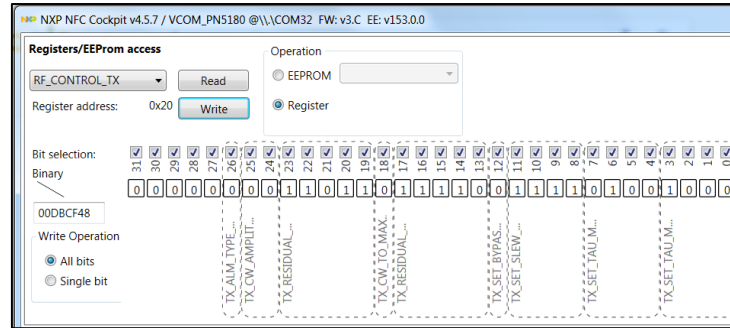
EMV L1 Analog - Waveform tests

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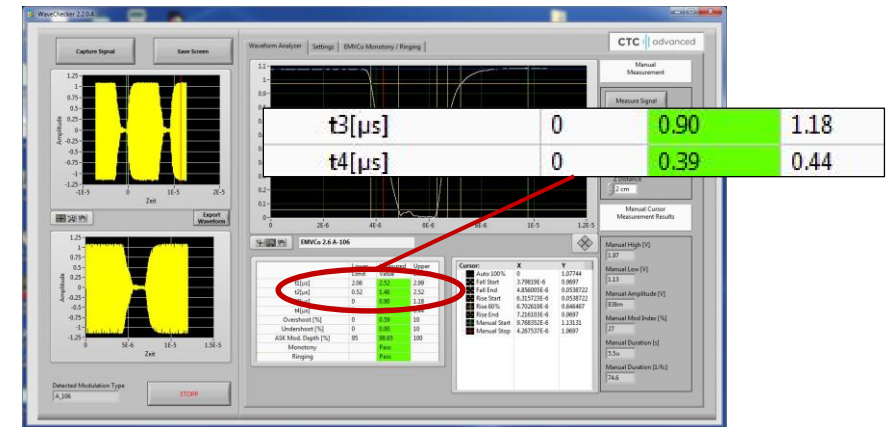
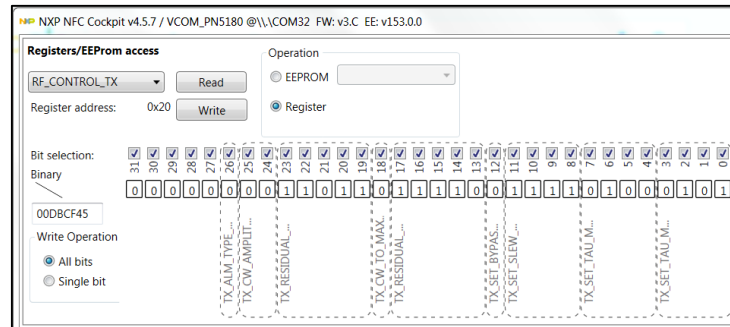
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- TA128: Overshoot



Decrease TAU_MOD_RISING



EMV L1 Analog - Wave shape tests

Waveform tests

1
Power tests

2
Waveform tests

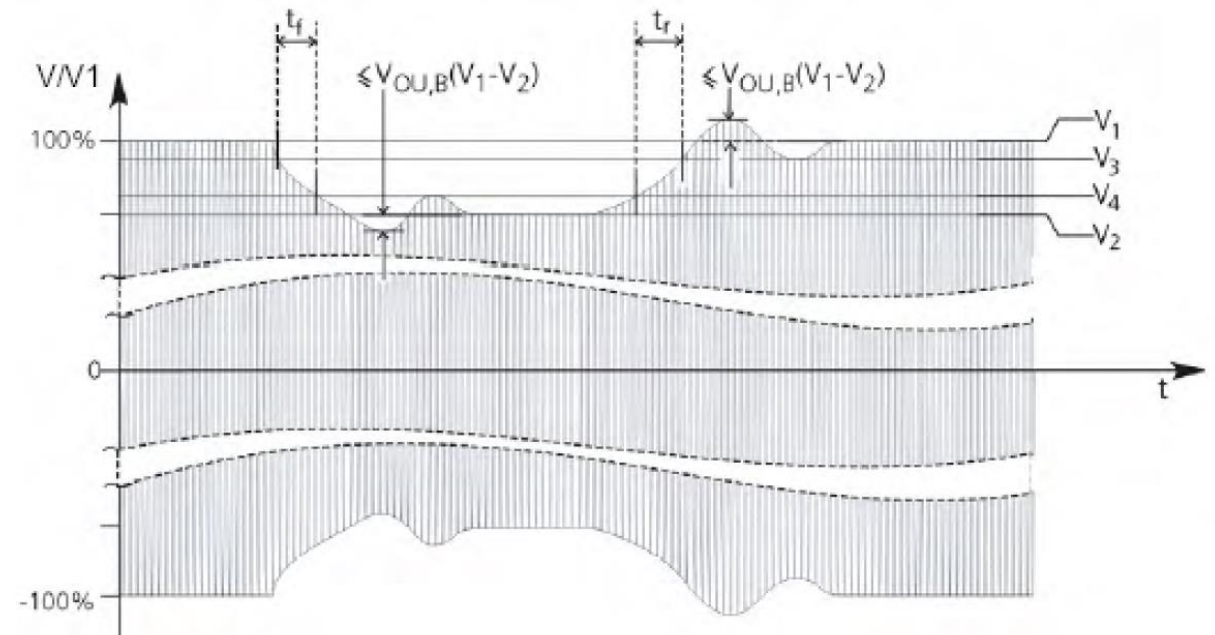
3
Reception tests

Type B:

- TB121: Modulation Index
- TB122: Fall time
- TB123: Rise time
- TB124: Monotonic Increase
- TB125: Monotonic Decrease
- TB126: Overshoots
- TB127: Undershoots

Relevant PN5180 parameters:

- TX_RESIDUAL_CARRIER (RF_CONTROL_TX)
- TX_CLK_MODE_RM (RF_CONTROL_TX_CLK)
- TX_UNDERSHOOT_CONFIG
- TX_OVERSHOOT_CONFIG



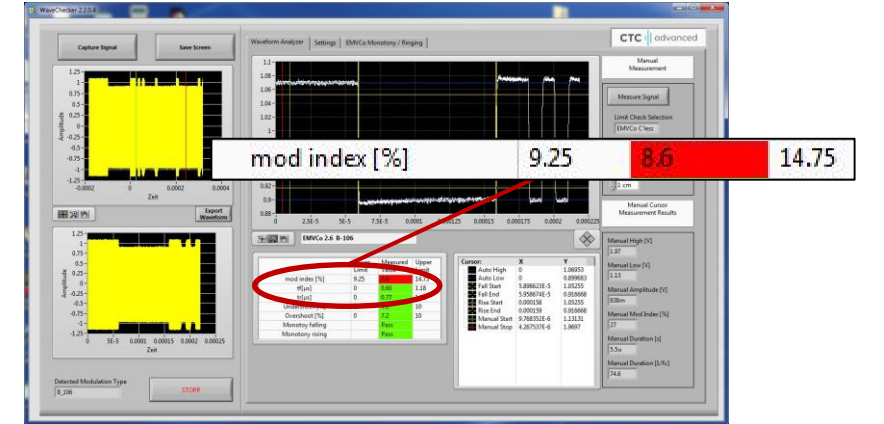
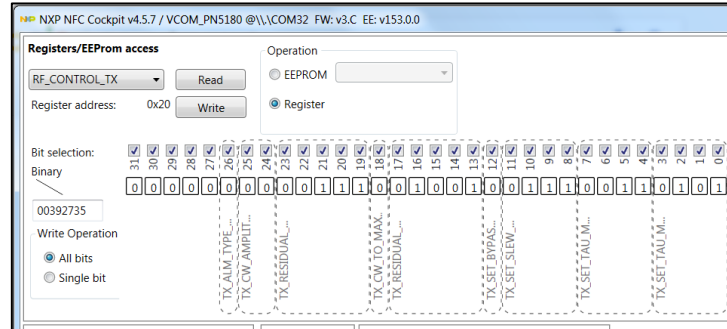
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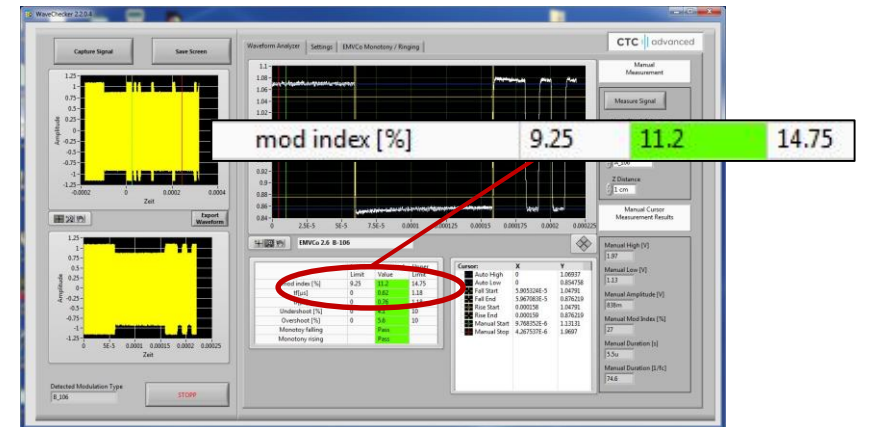
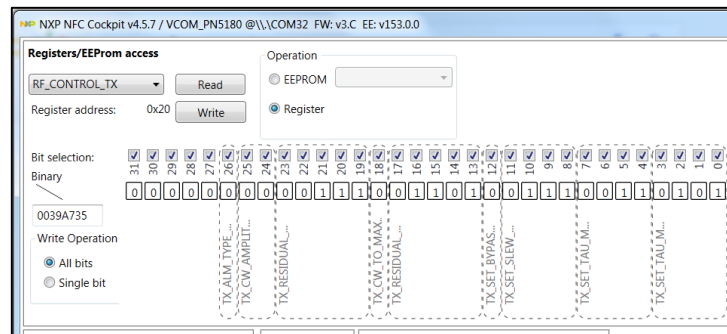
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Increase TX_RESIDUAL_CARRIER



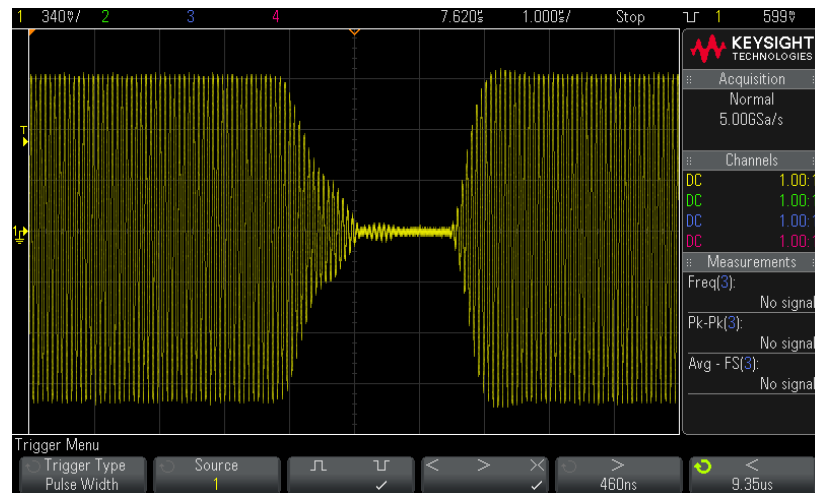
EMV L1 Analog - Waveform tests

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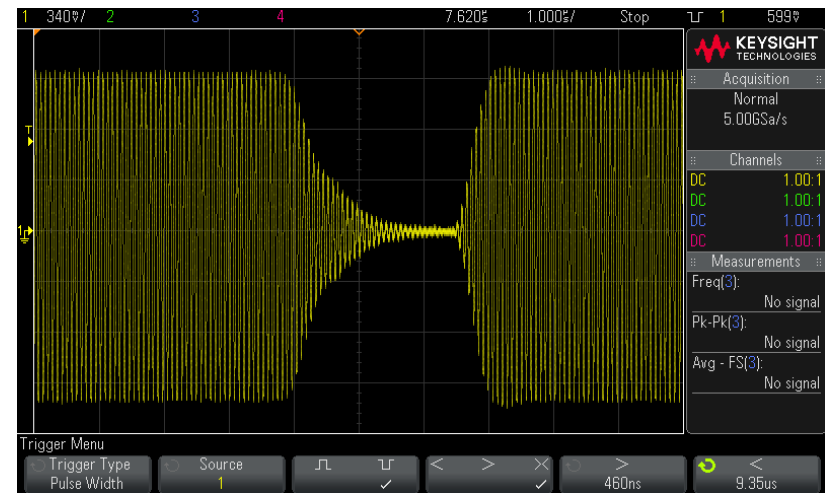
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Other relevant PN5180 parameters

TX_CLK_MODE_RM



TX_CLK_MODE_RM = 001_{BIN}



TX_CLK_MODE_RM = 101_{BIN}

EMV L1 Analog - Waveform tests

Debugging tests



Adaptative Waveform Control (AWC)

PN5180 functionality that allows the device manufacturer to set different register parameters depending on the gear and the protocol used.

Parameters included:

- TX_TAU_MOD_FALLING
- TX_TAU_MOD_RISING
- TX_RESIDUAL_CARRIER

Example of AWC configuration for Type B

Parameter	Gear 0	Gear 1	Gear 2	Gear 3
TX_RES_CARRIER	18	18	14	14
MOD_FALLING	5	3	3	3
MOD_RISING	5	6	6	6

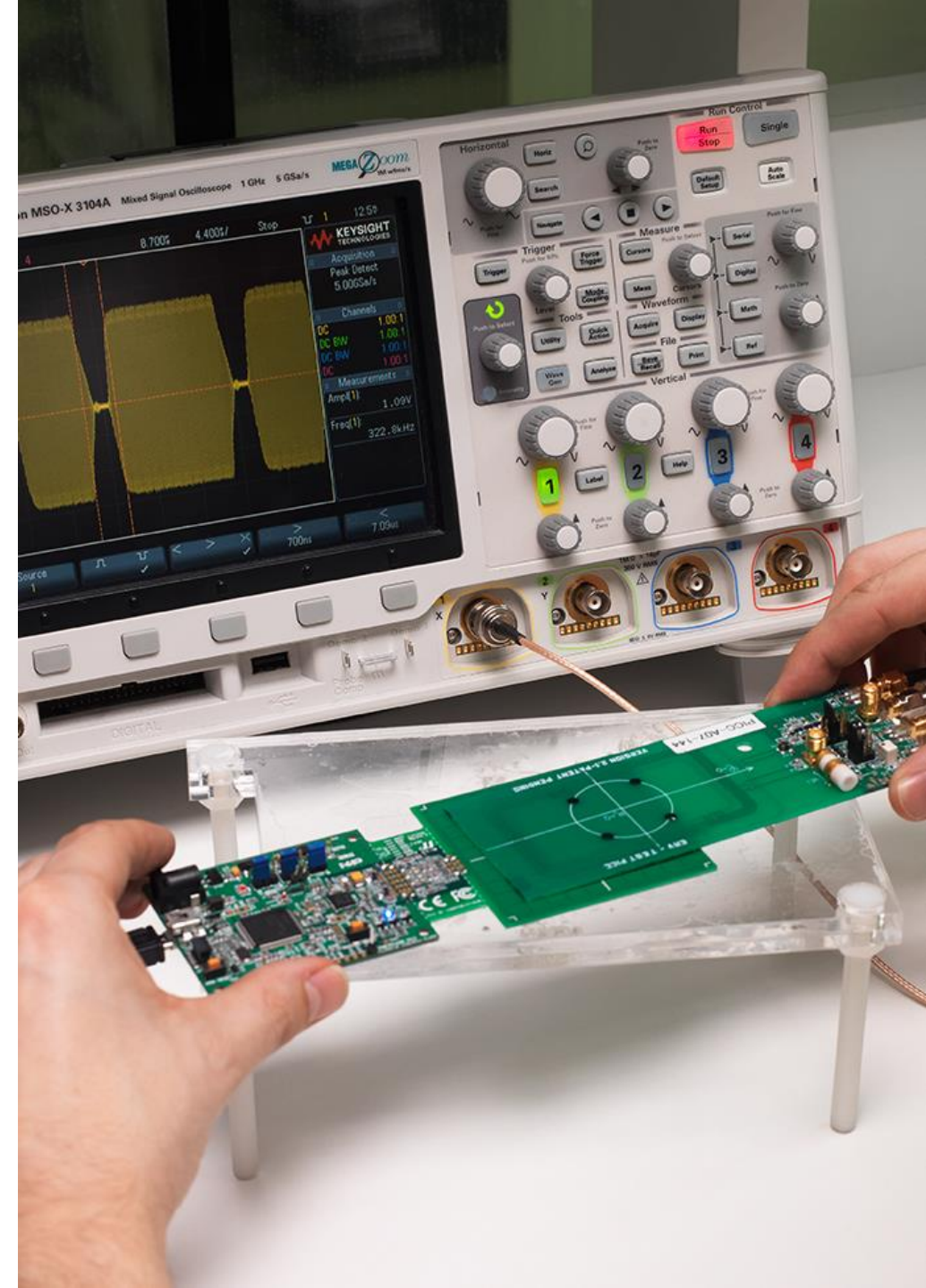
EMV L1 Analog Reception tests



EMV L1 Analog - Reception tests

Content

- Evaluation tools
- Test setup
- Performing tests
- Debugging hints



EMV L1 Analog – Reception tests

Evaluation tools

1
Power tests

2
Waveform tests

3
Reception tests

Option 1

EMVCo Analog L1 Testbench



Option 2

Reference PICC + Waveform Generator + Evaluation SW

Suggestion:

CETECOM Wave Player SW

PC tool that uses the waveform generator to inject the modulated responses into the reference PICC.

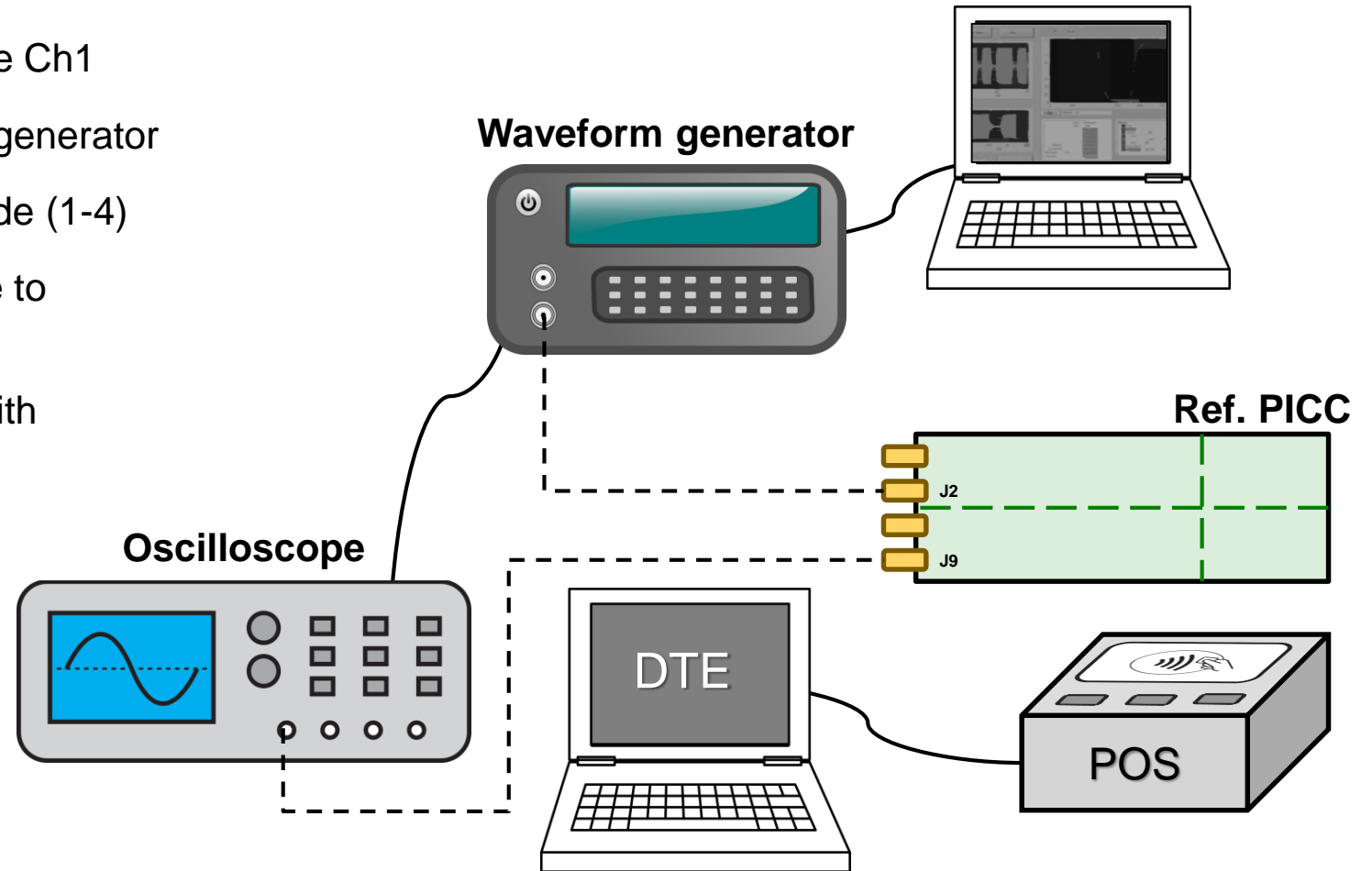


EMV L1 Analog - Reception tests

Test setup

1 Power tests	2 Waveform tests	3 Reception tests
------------------	---------------------	----------------------

1. Connect J9 of ref PICC to oscilloscope Ch1
2. Connect J2 of ref PICC to waveform generator
3. Set ref PICC J8 in non-linear load mode (1-4)
4. Connect Ext.Trigger from oscilloscope to waveform generator
5. Connect waveform generator to PC with CETECOM SW



EMV L1 Analog – Reception tests

Performing tests



Reception tests:

- Tx131: Minimum positive modulation
- Tx133 - Maximum positive modulation
- Tx135 - Minimum negative modulation
- Tx137 - Maximum negative modulation

Relevant PN5180 parameters:

- RX_GAIN (RF_CONTROL_RX)
- RX_HPCF (RF_CONTROL_RX)
- MIN_LEVEL (SIGPRO_RM_CONFIG)
- MIN_LEVELP (SIGPRO_RM_CONFIG)

Procedure:

- Use WavePlayer to select amplitude and polarity of the response
- Check that response is correctly received

Test Code	Test Name	0	0	0	0	0	1	1	1	1	1	2	2	2	2	2	3	3	3	3	3	4	4	4	4	4
		0	1	1	1	1	0	2	2	2	2	0	2	2	2	2	0	2	2	2	2	0	4	4	4	4
		0	0	3	6	9	0	0	3	6	9	0	0	3	6	9	0	0	3	6	9	0	0	3	6	9
TAB111	Power Transfer																									
TA121	t1																									
TA122	Monotonic Decrease																									
TA123	Ringing																									
TA124	t2																									
TA125	t3 and t4																									
TA127	Monotonic Increase																									
TA128	Overshoot																									
TA131	Vs1pp Min Positive																									
TA132	Vs2pp Min Positive																									
TA133	Vs1pp Max Positive																									
TA134	Vs2pp Max Positive																									
TA135	Vs1pp Min Negative																									
TA136	Vs2pp Min Negative																									
TA137	Vs1pp Max Negative																									
TA138	Vs2pp Max Negative																									
TB121	Modulation Index																									
TB122	Fall Time																									
TB123	Rise Time																									
TB124	Monotonic Increase																									
TB125	Monotonic Decrease																									
TB126	Overshoots																									
TB127	Undershoots																									
TB131	Vs1pp Min Positive																									
TB132	Vs2pp Min Positive																									
TB133	Vs1pp Max Positive																									
TB134	Vs2pp Max Positive																									
TB135	Vs1pp Min Negative																									
TB136	Vs2pp Min Negative																									
TB137	Vs1pp Max Negative																									
TB138	Vs2pp Max Negative																									

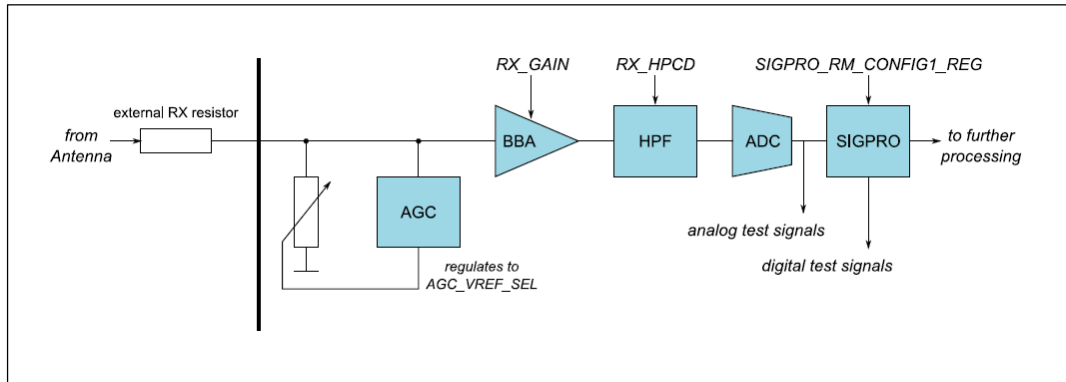
EMV L1 Analog – Reception tests

Debugging hints

Debugging procedure:

- Change reception parameters to find a good value
- Change Rx resistor:
 - Decrease resistor to increase sensibility

PN1580 Receiver block diagram



PN1580 Receiver filter characteristics

RF_CONTROL_RX Low nibble	rcv_gain	rcv_hpcf	HPCF (kHz)	LPCF (MHz)	Gain (dB20)	Bandwidth h (MHz)
3	03	00	39	3.1	60	3.1
7	03	01	78	3.2	59	3.1
B	03	02	144	3.5	58	3.3
F	03	03	260	4.1	56	3.8
2	02	00	42	3.1	51	3.1
6	02	01	82	3.3	51	3.2
A	02	02	150	3.7	49	3.5
E	02	03	271	4.3	47	4.0
1	01	00	41	3.7	43	3.7
5	01	01	82	4.0	42	3.9
9	01	02	151	4.5	41	4.3
D	01	03	276	5.5	39	5.2
0	00	00	42	3.8	35	3.8
4	00	01	84	4.1	34	4.0
8	00	02	154	4.7	33	4.5
C	00	03	281	5.7	31	5.4

EMV L1 Analog - Reception tests

Debugging hints



Adaptative Receiver Control (ARC)

PN5180 functionality that allows the use of different receiver configurations depending on the gear and the protocol used.

Parameters included:

- RX_GAIN
- RX_HPCF
- MIN_LEVEL
- MIN_LEVELP

Example of ARC configuration for Type B

Parameter	Gear 0	Gear 1	Gear 2	Gear 3
MIN_LEVEL	3	2	2	2
MIN_LEVEL_P	8	8	8	8
RX_HPCF	1	0	0	0
RX_GAIN	3	3	2	2

EMV L1 Analog - Reception tests

Debugging hints

1
Power tests

2
Waveform tests

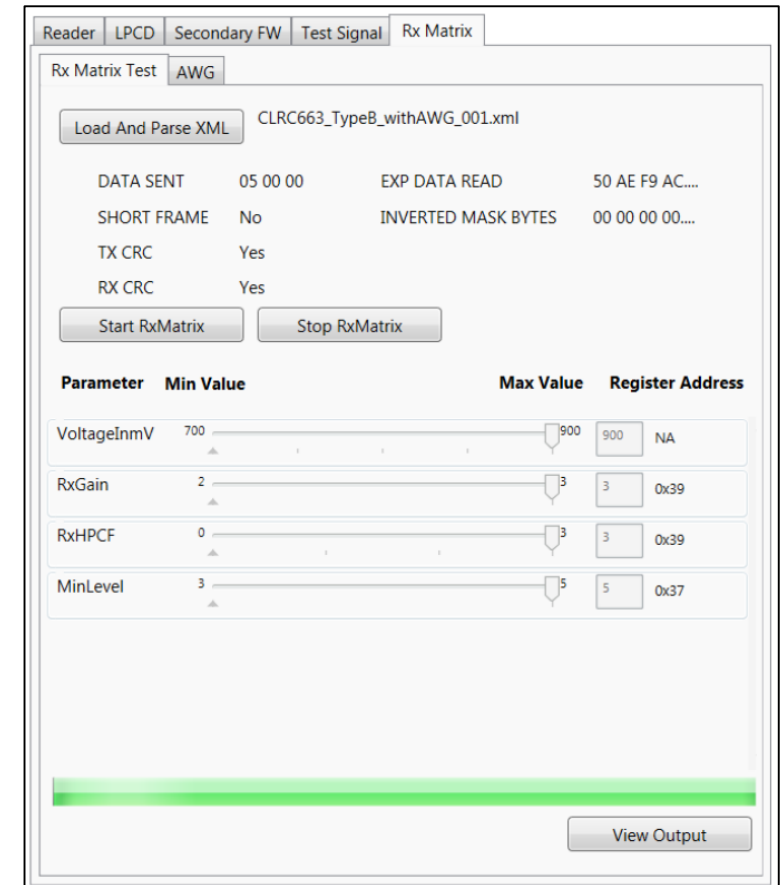
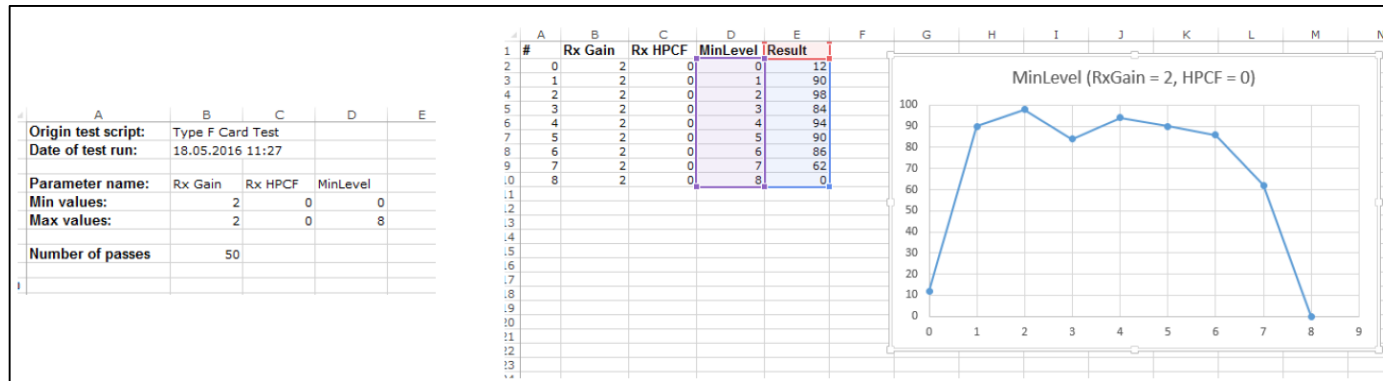
3
Reception tests

Rx Matrix tool

Software tool integrated in the NFC Cockpit platform to automatically test different receiver configurations.

Characteristics:

- Can be connected to an AWG to automate the process
- Allows you to select the parameters to change and the range of values
- Select the expected response from the AWG
- Generates a test report with the success ratio for every configuration

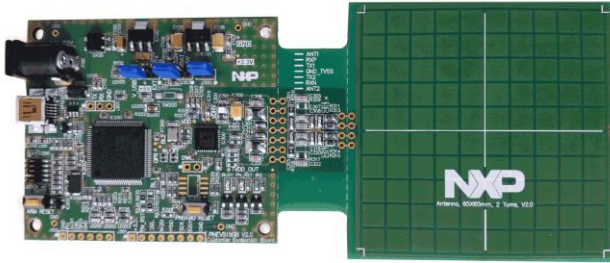


PN5180 Ecosystem



PN5180 Ecosystem

PN5180 Product support package



PN5180 Demokit

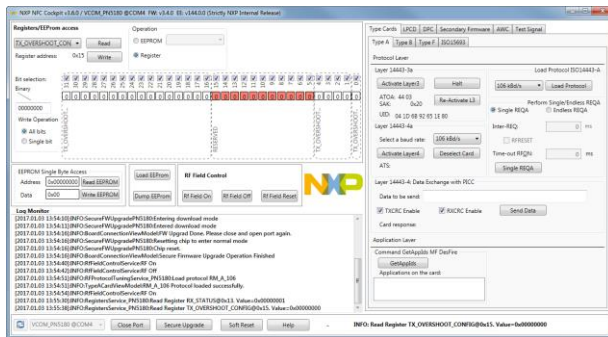
- PN5180 NFC frontend development kit OM25180FDK

NFC Cockpit

- SW3524 - Installer package PN5180 NFC Cockpit v2.2

PN5180 Documentation

- PN5180 - Product datasheet
- AN11742 - PN5180 Dynamic Power Control
- AN11744 - PN5180 evaluation board quick start guide
- AN11740 - PN5180 antenna design guide
- AN11741 - How to design an antenna with DPC
- UM10954 - PN5180 SW quick start guide
- SW3545 - PN5180 antenna design tools



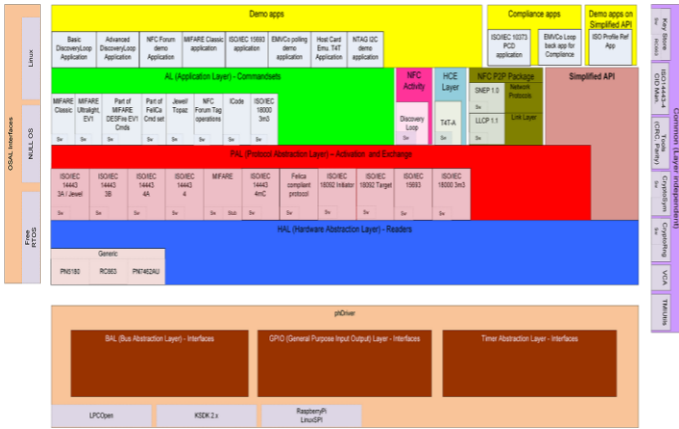
NFC Reader library

- SW3522 - NFC Reader Library for PNEV5180B including all SW examples

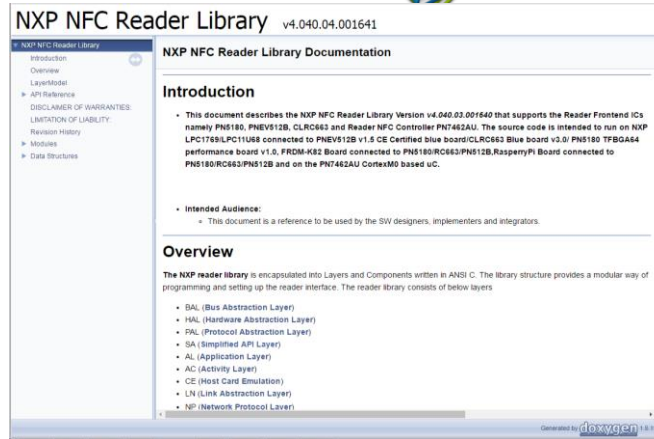
PN5180 Ecosystem

NFC Reader Library

NFC Reader Library API



Documentation



Software examples



NFC Reader Library API:

- Freely downloadable.
- Full implementation of all NFC protocols
- NDA version with full support for MIFARE DESFire EV2 and MIFARE Plus EV1
- SW package for MCUXpresso

Documentation:

- API documentation
- Generated from source file annotations
- Provided as HTML document

Software examples:

- BasicDiscoveryLoop
- AdvancedDiscoveryLoop
- NFCForum
- ISO15693
- EMVCo Loopback
-

PN5180 Ecosystem

NFC Reader Library

Some applications:

- Nfcrdlib_SimplifiedAPI_EMVCo → EMVCo digital L1
- Nfcrdlib_SimplifiedAPI_EMVCo_Analog → EMVCo analog L1

Configuration file: [phNxpNfcRdLib_Config.h](#)

All parameters involved in the loopback application are well documented and can be changed by user to correctly fit the specifications.

```
/* Default guard times used in Discovery Loop and NFCLIB (Simplified API).
 * As per Nfc Forum Activity and EMVCo Specification. */
#define PH_NXPNFCRDLIB_CONFIG_TYPEA_GT 5100U /**< Guard time configuration for Type A poll in Micro seconds.*/
#define PH_NXPNFCRDLIB_CONFIG_TYPEB_GT 5100U /**< Guard time configuration for Type B poll in Micro seconds.*/
#define PH_NXPNFCRDLIB_CONFIG_TYPEF_GT 20400U /**< Guard time configuration for Type F poll in Micro seconds.*/
#define PH_NXPNFCRDLIB_CONFIG_B_TO_F_GT 15300U /**< Guard time configuration for Type F poll preceded by Type B poll. */
#define PH_NXPNFCRDLIB_CONFIG_TYPEV_GT 5200U /**< Guard time configuration for Type V poll in Micro seconds.*/
#define PH_NXPNFCRDLIB_CONFIG_I18000P3M3_GT 10000U /**< Guard time configuration for 18000p3m3 poll in Micro seconds.*/

/* Used in Discovery Loop and NFCLIB (Simplified API) as per EMVCo Specification. */
#define PH_NXPNFCRDLIB_CONFIG_EMVCO_FIELD_OFF_DELAY_US 5100U /**< Wait time tP as per EMVCo specification. Simplified API EMVCo profile
uses this value for Card removal procedure. */
#define PH_NXPNFCRDLIB_CONFIG_EMVCO_REMOVAL_RETRY_COUNT 3U /**< Poll command retry count used in removal procedure of EMVCo profile. */
```

More support





NXP

Relevant resources regarding POS

Certification	NXP support	End customer
EMVCo L1 contact analog	Application notes; demo board; Report from test house Customer schematic validation	Final device needs to be tested at a certified lab
EMVCo L1 contact digital	Application note; source code; ICS example; internal test report Support on NXP stack integration Support on EMV test suite errors	Final device needs to be tested at a certified lab
EMVCo L2 contact	Link to partners for stack ; Pre integration support if NXP L1 stack is used	Final device needs to be tested at a certified lab

Certification	NXP support	End customer
EMVCo L1 contactless analog	Antenna design guide, loop back example; internal test report; demo board Antenna design support & RF support from CAS team	Final device needs to be tested at a certified lab
EMVCo L1 contactless digital	Source code; application note ICS example; internal test report Support on NXP stack integration Support on EMV test suite errors	Final device needs to be tested at a certified lab
EMVCo L2 contactless	Link to partners for stack ; Pre integration support if NXP L1 stack is used	Final device needs to be tested at a certified lab





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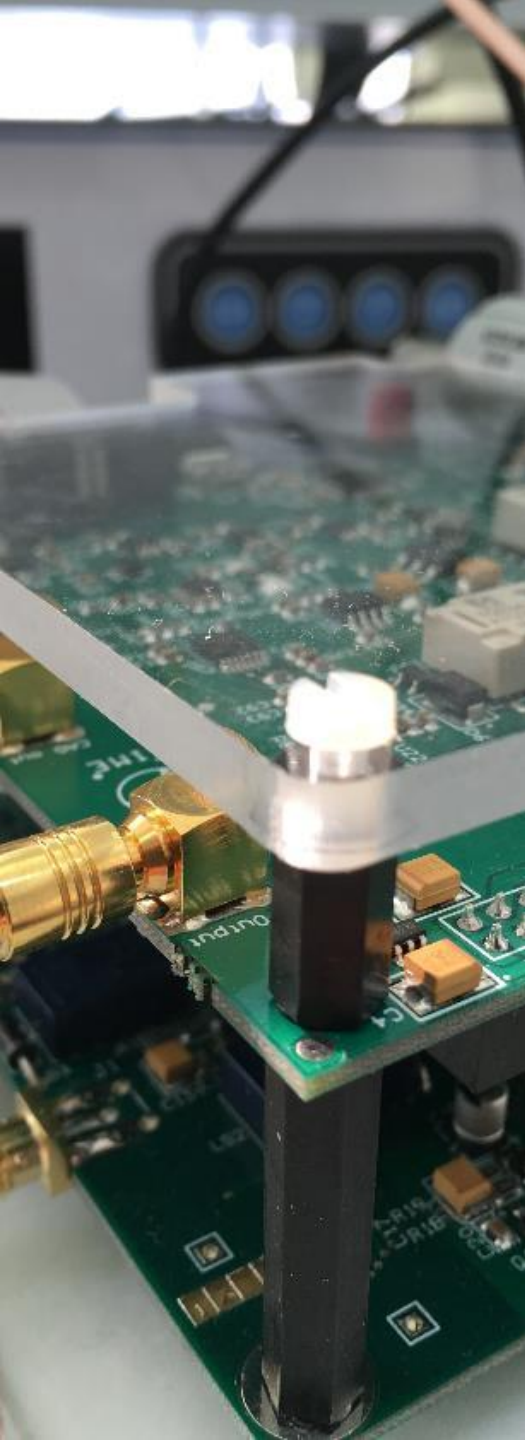
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